Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	Applicant(s)/Patent under Reexamination	
10/033,196	NAKAMURA ET AL.		
Examiner	Art Unit		
Jia W. Lu	2634		

SEARCHED				
Class	Subclass	Date	Examiner	
375	148	3/7/2005	JL	
375	225	3/7/2005	JL	

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
375	148	3/7/2005	JL		
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SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	3/7/2005	JL
INVENTORPSHIP	3/7/2005	JL